

Notice of References Cited		Application/Control No.	Applicant(s)/Patent Under Reexamination	
		10/717,119	VAN NIEUWSTADT ET AL.	
Examiner		Art Unit		Page 1 of 1
Eric S. McCall		2855		

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-2004/0040282	03-2004	Zhu, Dannie	060/276
	B	US-2003/0103886	06-2003	Dou, Danan	423/239.1
	C	US-2003/0041594	03-2003	van Nieuwstadt, Michiel Jacques	60/286
	D	US-6,581,371	06-2003	Orzel et al.	60/277
	E	US-6,050,128	04-2000	Hamburg et al.	73/23.32
	F	US-5,998,210	12-1999	Hepburn et al.	436/37
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.